- 1. (Currently Amended) A mask, wherein said mask comprises:
 - a substrate;
 - a cooling layer on said substrate; and
 - a planarizing layer on said cooling layer; and
 - a mask absorber above said planarizing layer.
- wherein said substrate, said cooling layer, said planarizing layer, and said mask absorber comprise an integrated structure.
- 2. (Original) The mask of claim 1, wherein said substrate structure material comprises a coefficient of thermal expansion less than 1 parts per billion per degree Celsius.
- 3. (Original) The mask of claim 1, wherein said substrate structure material comprises a coefficient of thermal expansion between the range of 1 parts per million per degree Celsius and 5 parts per billion per degree Celsius.
- 4. (Original) The mask of claim 1, wherein said mask comprises an extreme ultraviolet mask.
- 5. (Original) The mask of claim 1, wherein said cooling layer comprises a thermoelectric module.
- 6. (Original) The mask of claim 1, wherein said cooling layer comprises semiconductor pellets.
- 7. (Original) The mask of claim 4, wherein said semiconductor pellets comprise p-type pellets and n-type pellets.
- 8. (Original) The mask of claim 1, wherein said cooling layer comprises a thermoelectric

integrated structure.

cooler.

- 9. (Original) The mask of claim 1, wherein said planarizing layer has height variations not exceeding 50 nm.
- 10. (Original) The mask of claim 1, where said planarizing layer supports an extreme ultraviolet multilayer reflector.
- 11. (Currently Amended) The mask of claim 1, where said planarizing layer supports a said mask absorber.
- 12. (Currently Amended) A mask blank comprising:
 a substrate having at least one cooling channel; and
 a cooling fluid within said cooling channel; and
 a mask absorber above said substrate,
 wherein said substrate, said cooling channel, and said mask absorber comprise an
- 13. (Original) The mask blank of claim 12, wherein said cooling fluid comprises water.
- 14. (Original) The mask blank of claim 12, wherein said substrate comprises a low expansion ceramic.
- 15. (Original) The mask blank of claim 12, wherein said cooling channel has a cross section diameter of less than approximately 1 micron.
- (Original) The mask blank of claim 12, wherein said cooling channel has a cross section diameter of up to approximately 1 mm.

- (Original) The mask blank of claim 12, further comprising a cover material covering said 17. cooling channel.
- (Currently Amended) A method of making a mask blank, said method comprising: 18. forming at least one cooling channel in a mask substrate; and enclosing said channels with a cover material; and forming a mask absorber above said mask substrate layer, wherein said forming of said substrate, said cooling channel, and said mask absorber forms an integrated structure,
- (Original) The method of claim 18, wherein said forming of said cooling channel 19. comprises direct machining of said mask substrate.
- 20. (Original) The method of claim 18, wherein said forming of said cooling channel comprises sintering said mask substrate.